

TEP105-9

TEPAC PUBLICATION

Line Profile Measurements in Shadow Mask and Other Structured Screen Cathode Ray Tubes

TEP105-9

JANUARY 1987

ELECTRONIC INDUSTRIES ASSOCIATION
ENGINEERING DEPARTMENT



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Published by

ELECTRONIC INDUSTRIES ASSOCIATION
Engineering Department
2001 Eye Street, N.W.
Washington, D.C. 20006

PRICE: \$5.00

Published in U.S.A.



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This publication was formulated under the cognizance of the JT-20 Committee on Electro-Optic Devices and approved by the Tube Engineering Panel Advisory Council (TEPAC).

The TEP-105 series of publications comprise a set of test methods developed for industrial cathode ray tubes. They are intended to be useful in evaluating cathode ray tubes with respect to parameters which are of interest to users of these devices.

It is expected that, at an appropriate time, this material will be forwarded to the US National Committee (USNC) of the IEC as a proposed revision, in part, of IEC 151-14.